Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK2837

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• Low drain–source ON resistance : RDS (ON) = 0.21 Ω (typ.)

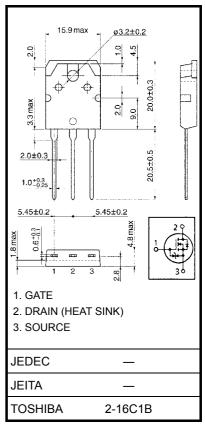
• High forward transfer admittance $: |Y_{fs}| = 17 \text{ S (typ.)}$

• Low leakage current $: I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(V_{DSS} = 500 \,\text{V})$

• Enhancement-mode : $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	500	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	500	V
Gate-source voltage		V_{GSS}	±30	V
Drain current	DC (Note 1)	ΙD	20	Α
	Pulse (Note 1)	I _{DP}	80	Α
Drain power dissipatio	n (Tc = 25°C)	P_{D}	150	W
Single pulse avalanche energy (Note 2)		E _{AS}	960	mJ
Avalanche current		I _{AR}	20	Α
Repetitive avalanche	energy (Note 3)	E _{AR}	15	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C / W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 4.08 mH, R_G = 25 Ω , I_{AR} = 20 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.



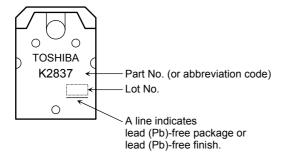
Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	I _G = ±10 μA, V _{DS} = 0 V	±30	_	_	V
Drain cut-off cur	rrent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br voltage	eakdown	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	500	_	ı	V
Gate threshold v	oltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source Ol	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 10 A		0.21	0.27	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 10 A	10	17	_	S
Input capacitano	e	C _{iss}		_	3720	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	340	_	pF
Output capacitance		Coss		_	1165	_	
Switching time	Rise time	t _r	$V_{GS} \xrightarrow[0V]{I_{D} = 10A} V_{OUT}$ $V_{DD} = 200V$ $V_{DD} = 200V$ $V_{DD} = 10\mu s$	_	30	_	
	Turn-on time	t _{on}		_	70	_	20
	Fall time	t _f		_	50	_	ns
	Turn-off time	t _{off}			290		
Total gate charge (gate-source plus gate-drain)		Qg		_	80	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$		48	_	nC
Gate-drain ("miller") Charge		Q _{gd}			32		

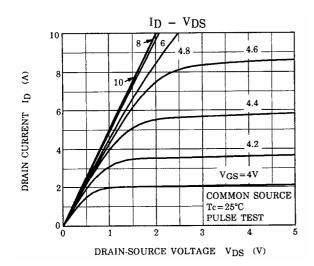
Source-Drain Ratings and Characteristics (Ta = 25°C)

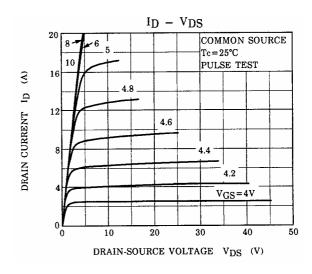
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	20	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	80	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 20 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 20 A, V _{GS} = 0 V	1	540	1	ns
Reverse recovery charge	Qrr	dl _{DR} / dt = 100 A / μs	_	5.4	_	μC

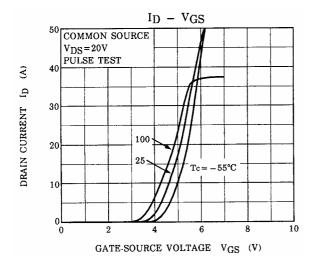
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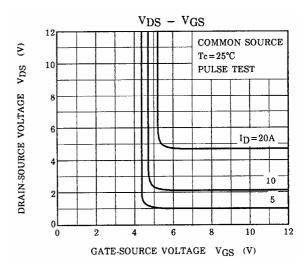


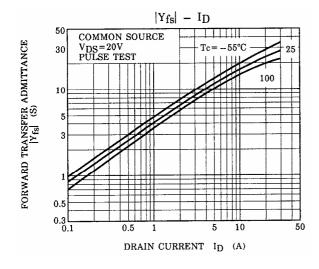
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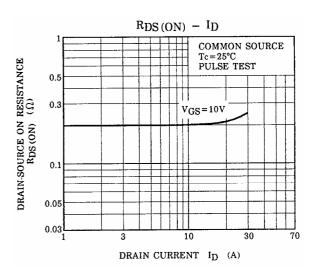


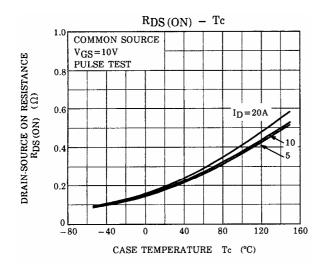


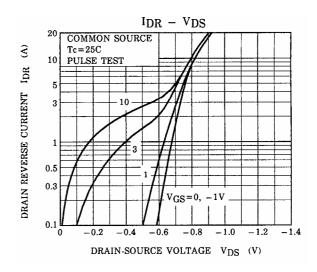


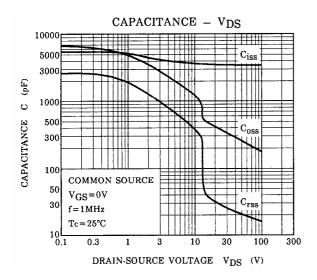


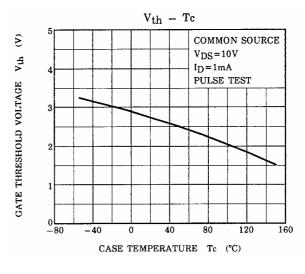


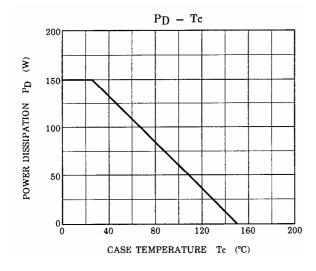


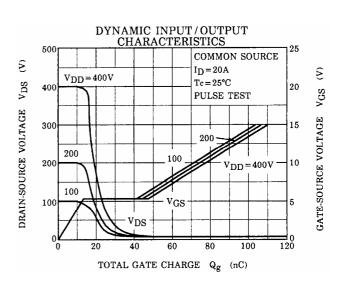


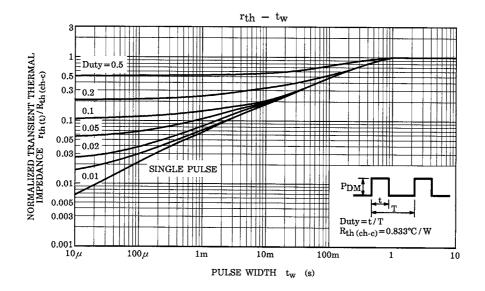


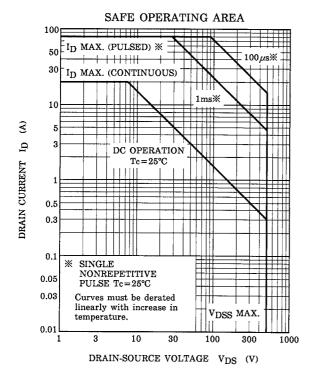


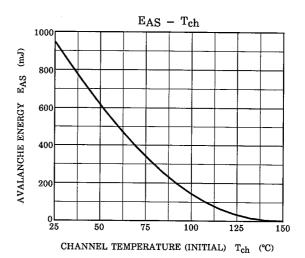


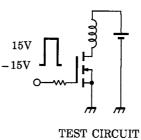


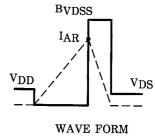












$$R_{G} = 25 \Omega$$

 $V_{DD} = 90 \text{ V, L} = 4.08 \text{ mH}$

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$$EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

RESTRICTIONS ON PRODUCT USE

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